DIMENSION® 2000 AND CUSTOM PBX ATTENDANT CONSOLE TESTS (PROC 510)

CONTENTS

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1. GENERAL

1.1 This section provides information for interogating and clearing CNSL Alarm via PROC 510.

1.2 Procedure 510 displays the dual-speed data channel (LC34B) and the high density dual-speed data channel (LC366) circuits associated with the attendant console failure that cause the Console Indicator (510) and Major Alarm to be turned on. This procedure performs loop-around tests on each dual-speed data channel circuit and on each attendant console. The Console Indicator is automatically turned off if all dual-speed data channels to the attendant consoles pass Test 2.

2. RECORDS

2.1 Form SD-97-1313 is required for recording the results of this test.

3. MAAP DISPLAY FIELD DESCRIPTION

3.1 The following describes the individual MAAP display fields related to PROC 510.

Field	Description
1	TEST NO. - Display active test number (maximum of 3) per the following encodes:

ENCODE	DESCRIPTION
1	Displays failure history.
2	Tests all circuits.
3	Tests a particular circuit (as displayed in fields 2,3 and 4).

3.1 (Cont'd)

Field	Description
2, 3, 4	Equipment location of LC34B or LC366 associated with the failing (or to be tested) console.

CARR TYPE	DESCRIPTION
0	Basic Common Control Carrier (J58882AC-1 or J58882AH-1)
1	First Growth Control Carrier or Basic Common Control Carrier (J5882 AD-1 or J58881 AH-1)
2	Second Growth Carrier (J58882AG-1)

5	Failed Console.
6	Failure Codes 0 = Pass 1 = On-line periodic dual-speed data channel circuit 2 = Addressing 3 = Loop-around console 4 = Addressng 5 = Message echo
7	Number of consoles in system.
8	(Tests 1 and 2), number of console failed.
9	(Tests 1 and 2), failed console index: 0 = All failure combined (Test 1) Greater than 0 = Individual failures (maximum of 6 for Test 1)
10	(Test 1), approximate failure rate (99 per hour maximum)
11	(Test 1), Number of hours since failure started - to nearest hour (17 hours maximum)
12, 13	(Test 1), Time since last failure - to nearest minute (136 hours, 31 minutes maximum)

4. MAAP CONTROL KEY SEQUENCES

4.1 PROC No. 5, 1, 0, ENTER - causes program of PROC 510 to be loaded into memory from tape for execution.

4.2 RESET - Starts the procedure from its beginning.

4.3 NEXT TEST - Advance to the next test number.

4.4 EXECUTE - Starts the displayed test.

4.5 NEXT CIRCUIT - Advances to the next failing circuit (Tests 1 and 2).
- Advances to the next equipped attendant console dual-speed data channel within the carrier specified in Field 2 (Test 3).

4.6 NEXT UNIT - Advances to the first circuit in the next control carrier (Test 3).

4.7 STOP - Stops the testing (Tests 2 and 3).

4.8 CLEAR DATA; EXECUTE - Clears the failure history (Test 1).

5. REPAIR PROCEDURE

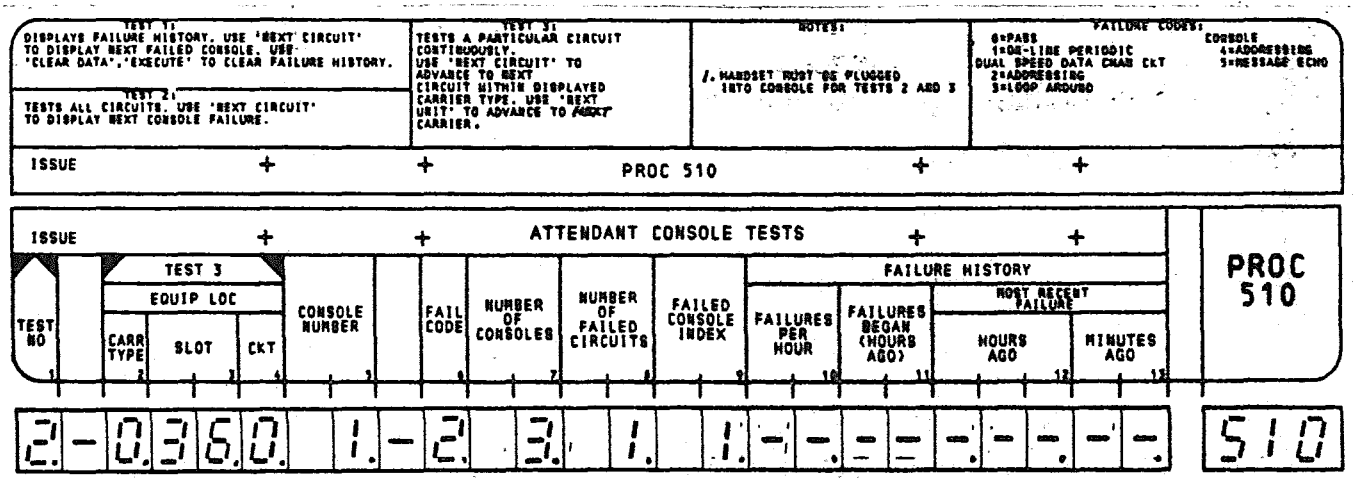
5.1 Make sure the headsets are plugged in. Execute Test 1 and record the failure history generated by on-line maintenance (last 6 failures). Execute Test 2 and record the results. If a failure occurs, use steps 5.1.1 and 5.1.2 below to repair the fault. If there are no failures, use Test 3 to continuously test each circuit displayed in Test 1 to verify if intermittent faults exist. If they do, use steps 5.1.1 and 5.1.2 to repair the failure.

5.1.1 Replace LC34B (low speed option) as indicated on the MAAP (use the HALT/GO sequence).

5.1.2 Check the voltages on CP MW-1.

a. If they are correct, replace CP MN-4B.
b. If they are incorrect, replace CP MW-1.

6. PROC 510 FLIP CHART



Reason for Issue:

New Section

Manager, Denver PBX PECC